Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/687,643	MINO, TETSUYA	
Examiner	Art Unit	
Paul D. Kim	3729	

SEARCHED				
Class	Subclass	Date	Examiner	
29	603.11 603.13- 603.16 603.18	7/5/2005	PK	
360	121 122	7/5/2005	PK	
	126 317			
427	127 128			
204	192.32- 19	7/5/2005	PK	
216	22			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Reviewed Parent Application 09/150,206 (US PAT. 6,188,544) 09/734,758 (ABN)	7/5/2005	PK
Textr Search EAST/NPL (IEEE)	7/6/2005	PK
Updated Text Search (EAST)	11/14/2005	PK